



## 512K X 8 BIT LOW POWER CMOS SRAM

### FEATURES

- Access time : 55 ns
- Low power consumption:  
Operating current : 30/20mA (TYP.)  
Standby current : 4  $\mu$ A (TYP.) C-version
- Single 2.7V ~ 5.5V power supply
- Fully Compatible with all Competitors 5V product
- Fully Compatible with all Competitors 3.3V product
- Fully static operation
- Tri-state output
- Data retention voltage : 2.0V (MIN.)
- **All products ROHS Compliant**
- Package    32-pin 450 mil SOP  
                  32-pin 8mm x 20mm TSOP-I  
                  32-pin 600 mil P-DIP  
                  32-pin 8mm x 13.4mm sTSOP  
                  \* 36-ball 6mm x 8mm TFBGA  
                  \*

Coming  
Soon!

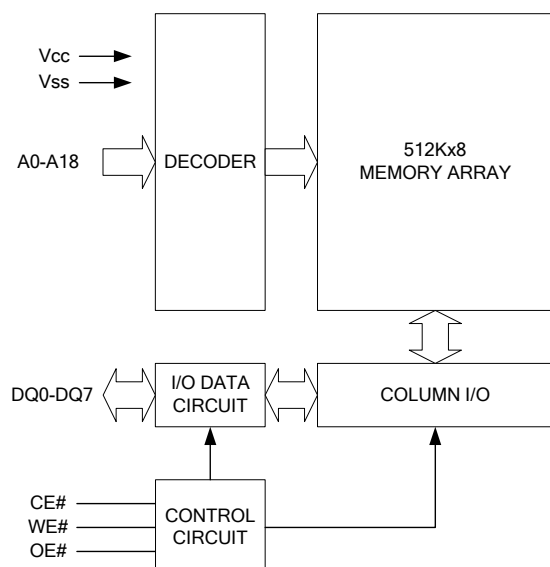
### GENERAL DESCRIPTION

The AS6C4008 is a 4,194,304-bit low power CMOS static random access memory organized as 524,288 words by 8 bits. It is fabricated using very high performance, high reliability CMOS technology. Its standby current is stable within the range of operating temperature.

The AS6C4008 is well designed for very low power system applications, and particularly well suited for battery back-up non-volatile memory application.

The AS6C4008 operates from a single power supply of 2.7V ~ 5.5V

### FUNCTIONAL BLOCK DIAGRAM

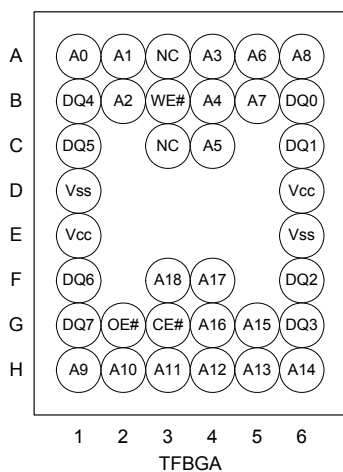
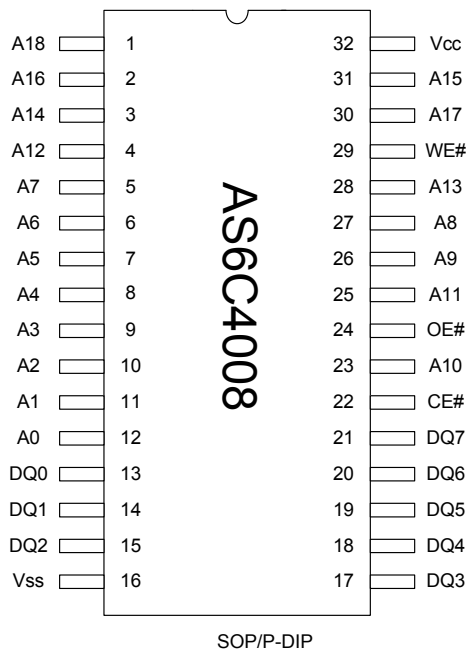


### PIN DESCRIPTION\*\*

| SYMBOL    | DESCRIPTION         |
|-----------|---------------------|
| A0 - A18  | Address Inputs      |
| DQ0 – DQ7 | Data Inputs/Outputs |
| CE#       | Chip Enable Inputs  |
| WE#       | Write Enable Input  |
| OE#       | Output Enable Input |
| Vcc       | Power Supply        |
| Vss       | Ground              |
| NC        | No Connection       |



## 512K X 8 BIT LOW POWER CMOS SRAM

**PIN CONFIGURATION**



## 512K X 8 BIT LOW POWER CMOS SRAM

**ABSOLUTE MAXIMUM RATINGS\***

| PARAMETER                                        | SYMBOL              | RATING             | UNIT |
|--------------------------------------------------|---------------------|--------------------|------|
| Terminal Voltage with Respect to V <sub>SS</sub> | V <sub>TERM</sub>   | -0.5 to 6.5        | V    |
| Operating Temperature                            | T <sub>A</sub>      | 0 to 70(C grade)   | °C   |
|                                                  |                     |                    |      |
|                                                  |                     | -40 to 85(I grade) |      |
| Storage Temperature                              | T <sub>STG</sub>    | -65 to 150         | °C   |
| Power Dissipation                                | P <sub>D</sub>      | 1                  | W    |
| DC Output Current                                | I <sub>OUT</sub>    | 50                 | mA   |
| Soldering Temperature (under 10 sec)             | T <sub>SOLDER</sub> | 260                | °C   |

\*Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to the absolute maximum rating conditions for extended period may affect device reliability.

**TRUTH TABLE**

| MODE           | CE# | OE# | WE# | I/O OPERATION    | SUPPLY CURRENT                     |
|----------------|-----|-----|-----|------------------|------------------------------------|
| Standby        | H   | X   | X   | High-Z           | I <sub>SB1</sub>                   |
| Output Disable | L   | H   | H   | High-Z           | I <sub>CC</sub> , I <sub>CC1</sub> |
| Read           | L   | L   | H   | D <sub>OUT</sub> | I <sub>CC</sub> , I <sub>CC1</sub> |
| Write          | L   | X   | L   | D <sub>IN</sub>  | I <sub>CC</sub> , I <sub>CC1</sub> |

Note: H = V<sub>IH</sub>, L = V<sub>IL</sub>, X = Don't care.

**DC ELECTRICAL CHARACTERISTICS**

| PARAMETER                              | SYMBOL                        | TEST CONDITION                                                                                          |      | MIN.                 | TYP. <sup>*3</sup> | MAX.                 | UNIT |
|----------------------------------------|-------------------------------|---------------------------------------------------------------------------------------------------------|------|----------------------|--------------------|----------------------|------|
| Supply Voltage                         | V <sub>CC</sub>               |                                                                                                         |      | 2.7                  | 3.0                | 5.5                  | V    |
| Input High Voltage                     | V <sub>IH</sub> <sup>*1</sup> |                                                                                                         |      | 0.7* V <sub>CC</sub> | -                  | V <sub>CC</sub> +0.3 | V    |
| Input Low Voltage                      | V <sub>IL</sub> <sup>*1</sup> |                                                                                                         |      | - 0.2                | -                  | 0.6                  | V    |
| Input Leakage Current                  | I <sub>LI</sub>               | V <sub>CC</sub> ≥ V <sub>IN</sub> ≥ V <sub>SS</sub>                                                     |      | - 1                  | -                  | 1                    | μA   |
| Output Leakage Current                 | I <sub>LO</sub>               | V <sub>CC</sub> ≥ V <sub>OUT</sub> ≥ V <sub>SS</sub> ,<br>Output Disabled                               |      | - 1                  | -                  | 1                    | μA   |
| Output High Voltage                    | V <sub>OH</sub>               | I <sub>OH</sub> = -1mA                                                                                  |      | 2.4                  | -                  | -                    | V    |
| Output Low Voltage                     | V <sub>OL</sub>               | I <sub>OL</sub> = 2mA                                                                                   |      | -                    | -                  | 0.4                  | V    |
| Average Operating Power supply Current | I <sub>CC</sub>               | Cycle time = Min.<br>CE# = 0.2V, I <sub>I/O</sub> = 0mA<br>other pins at 0.2V or V <sub>CC</sub> - 0.2V | - 55 | -                    | 30                 | 60                   | mA   |
|                                        |                               |                                                                                                         |      |                      |                    |                      |      |
|                                        | I <sub>CC1</sub>              | Cycle time = 1μs<br>CE# = 0.2V, I <sub>I/O</sub> = 0mA<br>other pins at 0.2V or V <sub>CC</sub> - 0.2V  |      | -                    | 4                  | 10                   | mA   |
| Standby Power Supply Current           | I <sub>SB1</sub>              | CE# ≥ V <sub>CC</sub> - 0.2V                                                                            | *C   | -                    | 4                  | 50 <sup>*4</sup>     | μA   |
|                                        |                               |                                                                                                         | *I   | -                    | 4                  | 50 <sup>*4</sup>     | μA   |

Notes: 1. V<sub>IH</sub>(max) = V<sub>CC</sub> + 3.0V for pulse width less than 10ns. V<sub>IL</sub>(min) = V<sub>SS</sub> - 3.0V for pulse width less than 10ns.

2. Over/Undershoot specifications are characterized, not 100% tested.

3. Typical values are included for reference only and are not guaranteed or tested.

Typical values are measured at V<sub>CC</sub> = V<sub>CC</sub>(TYP.) and T<sub>A</sub> = 25°C

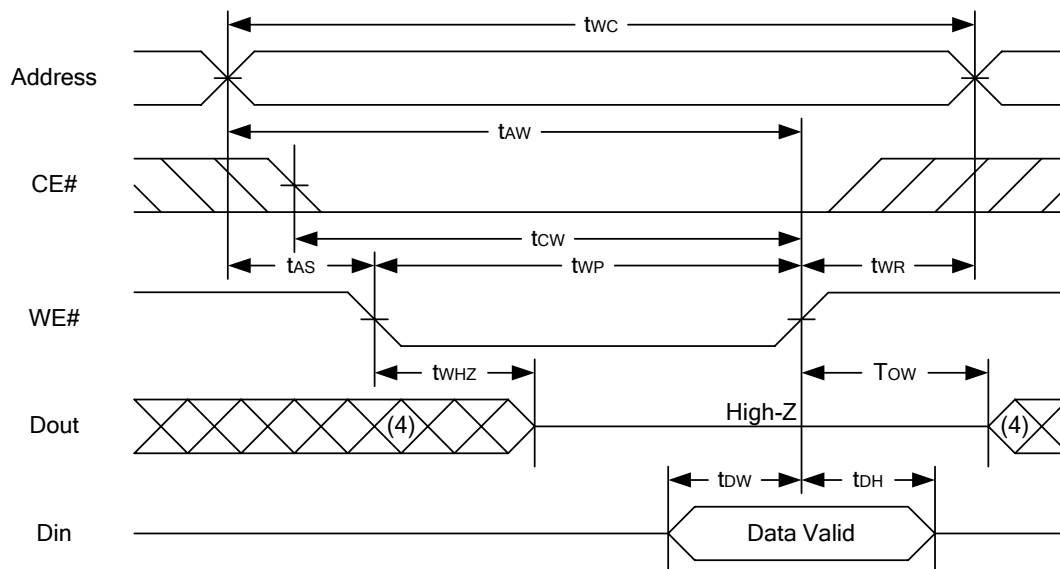
4. 25μA for special request

\*C=Commercial temperature/I = Industrial temperature

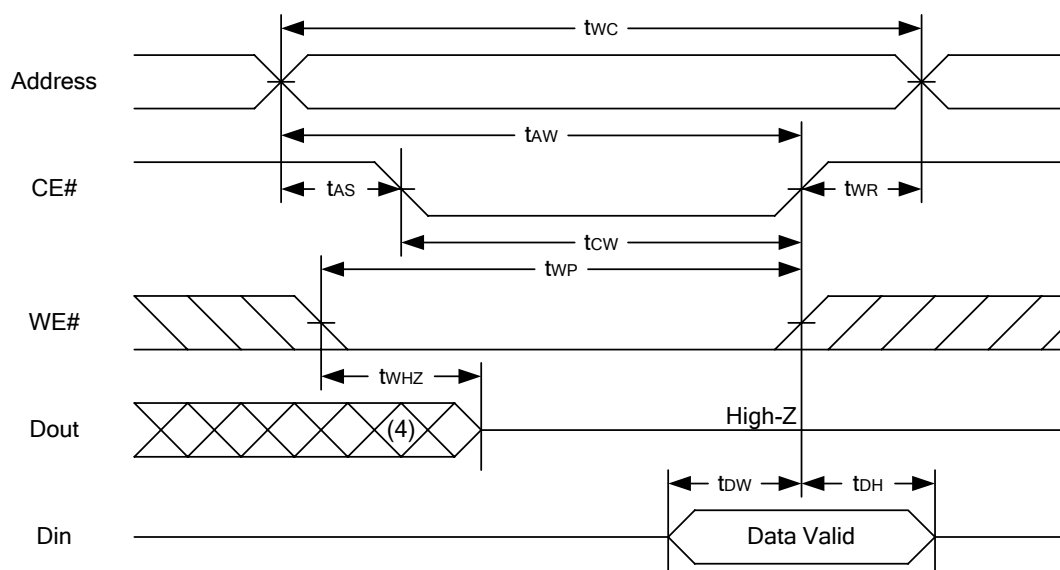


# 512K X 8 BIT LOW POWER CMOS SRAM

## WRITE CYCLE 1 (WE# Controlled) (1,2,3,5,6)



## WRITE CYCLE 2 (CE# Controlled) (1,2,5,6)



### Notes :

1. WE#, CE# must be high during all address transitions.
2. A write occurs during the overlap of a low CE#, low WE#.
3. During a WE# controlled write cycle with OE# low, twp must be greater than twhz + tdw to allow the drivers to turn off and data to be placed on the bus.
4. During this period, I/O pins are in the output state, and input signals must not be applied.
5. If the CE# low transition occurs simultaneously with or after WE# low transition, the outputs remain in a high impedance state.
6. tow and twhz are specified with CL = 5pF. Transition is measured  $\pm 500\text{mV}$  from steady state.

Rev. 1.1

**512K X 8 BIT LOW POWER CMOS SRAM****Notes:**

1.  $V_{IH}(\text{max}) = V_{CC} + 3.0\text{V}$  for pulse width less than 10ns.
2.  $V_{IL}(\text{min}) = V_{SS} - 3.0\text{V}$  for pulse width less than 10ns.
3. Over/Undershoot specifications are characterized, not 100% tested.
4. Typical values are included for reference only and are not guaranteed or tested.  
Typical values are measured at  $V_{CC} = V_{CC}(\text{TYP.})$  and  $T_A = 25^\circ\text{C}$ .

**CAPACITANCE ( $T_A = 25^\circ\text{C}$ ,  $f = 1.0\text{MHz}$ )**

| PARAMETER                | SYMBOL    | MIN. | MAX | UNIT |
|--------------------------|-----------|------|-----|------|
| Input Capacitance        | $C_{IN}$  | -    | 6   | pF   |
| Input/Output Capacitance | $C_{I/O}$ | -    | 8   | pF   |

Note : These parameters are guaranteed by device characterization, but not production tested.

**AC TEST CONDITIONS**

|                                          |                                                                              |
|------------------------------------------|------------------------------------------------------------------------------|
| Input Pulse Levels                       | 0.2V to $V_{CC} - 0.2\text{V}$                                               |
| Input Rise and Fall Times                | 3ns                                                                          |
| Input and Output Timing Reference Levels | 1.5V                                                                         |
| Output Load                              | $C_L = 30\text{pF} + 1\text{TTL}$ , $I_{OH}/I_{OL} = -1\text{mA}/2\text{mA}$ |

**AC ELECTRICAL CHARACTERISTICS****(1) READ CYCLE**

| PARAMETER                          | SYM.        |      |      | AS6C4008-55 |      |      |      | UNIT |
|------------------------------------|-------------|------|------|-------------|------|------|------|------|
|                                    |             | MIN. | MAX. | MIN.        | MAX. | MIN. | MAX. |      |
| Read Cycle Time                    | $t_{RC}$    |      |      | 55          | -    |      |      | ns   |
| Address Access Time                | $t_{AA}$    |      |      | -           | 55   |      |      | ns   |
| Chip Enable Access Time            | $t_{ACE}$   |      |      | -           | 55   |      |      | ns   |
| Output Enable Access Time          | $t_{OE}$    |      |      | -           | 30   |      |      | ns   |
| Chip Enable to Output in Low-Z     | $t_{CLZ}^*$ |      |      | 10          | -    |      |      | ns   |
| Output Enable to Output in Low-Z   | $t_{OLZ}^*$ |      |      | 5           | -    |      |      | ns   |
| Chip Disable to Output in High-Z   | $t_{CHZ}^*$ |      |      | -           | 20   |      |      | ns   |
| Output Disable to Output in High-Z | $t_{OHZ}^*$ |      |      | -           | 20   |      |      | ns   |
| Output Hold from Address Change    | $t_{OH}$    |      |      | 10          | -    |      |      | ns   |

**(2) WRITE CYCLE**

| PARAMETER                        | SYM.        |      |      | AS6C4008-55 |      |      |      | UNIT |
|----------------------------------|-------------|------|------|-------------|------|------|------|------|
|                                  |             | MIN. | MAX. | MIN.        | MAX. | MIN. | MAX. |      |
| Write Cycle Time                 | $t_{WC}$    |      |      | 55          | -    |      |      | ns   |
| Address Valid to End of Write    | $t_{AW}$    |      |      | 50          | -    |      |      | ns   |
| Chip Enable to End of Write      | $t_{CW}$    |      |      | 50          | -    |      |      | ns   |
| Address Set-up Time              | $t_{AS}$    |      |      | 0           | -    |      |      | ns   |
| Write Pulse Width                | $t_{WP}$    |      |      | 45          | -    |      |      | ns   |
| Write Recovery Time              | $t_{WR}$    |      |      | 0           | -    |      |      | ns   |
| Data to Write Time Overlap       | $t_{DW}$    |      |      | 25          | -    |      |      | ns   |
| Data Hold from End of Write Time | $t_{DH}$    |      |      | 0           | -    |      |      | ns   |
| Output Active from End of Write  | $t_{OW}^*$  |      |      | 5           | -    |      |      | ns   |
| Write to Output in High-Z        | $t_{WHZ}^*$ |      |      | -           | 20   |      |      | ns   |

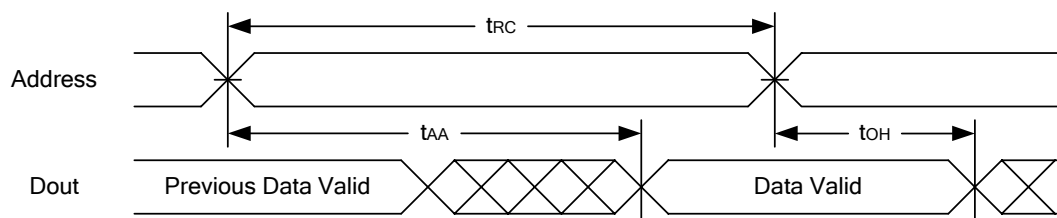
\*These parameters are guaranteed by device characterization, but not production tested.



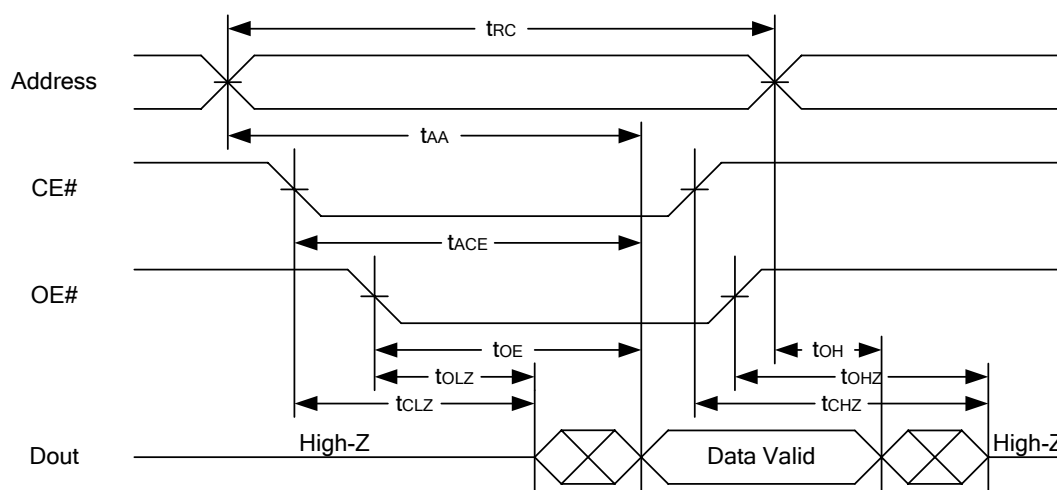
## 512K X 8 BIT LOW POWER CMOS SRAM

### TIMING WAVEFORMS

#### READ CYCLE 1 (Address Controlled) (1,2)



#### READ CYCLE 2 (CE# and OE# Controlled) (1,3,4,5)



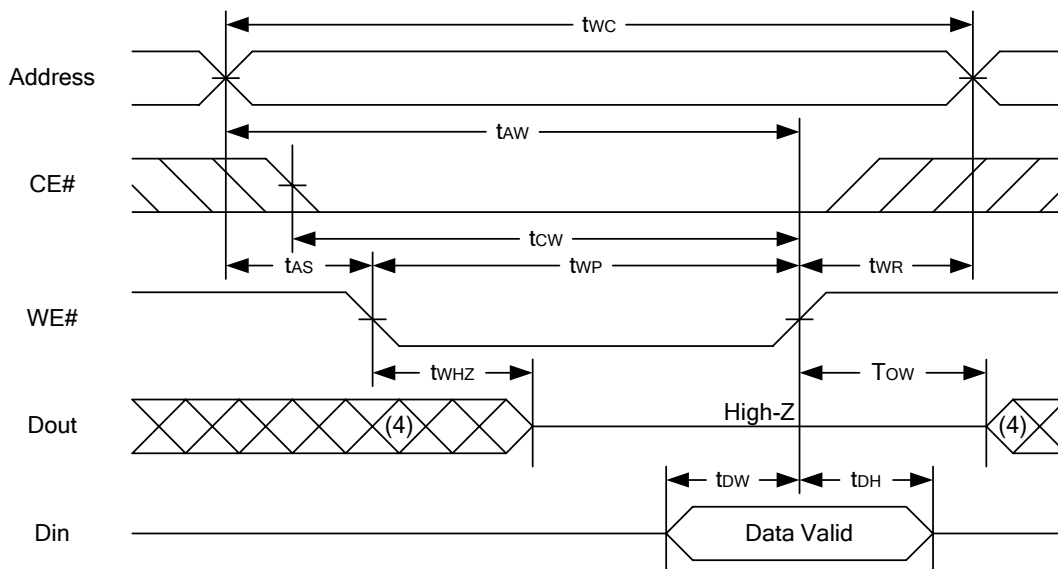
#### Notes :

1. WE# is high for read cycle.
2. Device is continuously selected OE# = low, CE# = low.
3. Address must be valid prior to or coincident with CE# = low; otherwise  $t_{AA}$  is the limiting parameter.
4.  $t_{CLZ}$ ,  $t_{OLZ}$ ,  $t_{CHZ}$  and  $t_{OHZ}$  are specified with  $C_L = 5\text{pF}$ . Transition is measured  $\pm 500\text{mV}$  from steady state.
5. At any given temperature and voltage condition,  $t_{CHZ}$  is less than  $t_{CLZ}$ ,  $t_{OHZ}$  is less than  $t_{OLZ}$ .

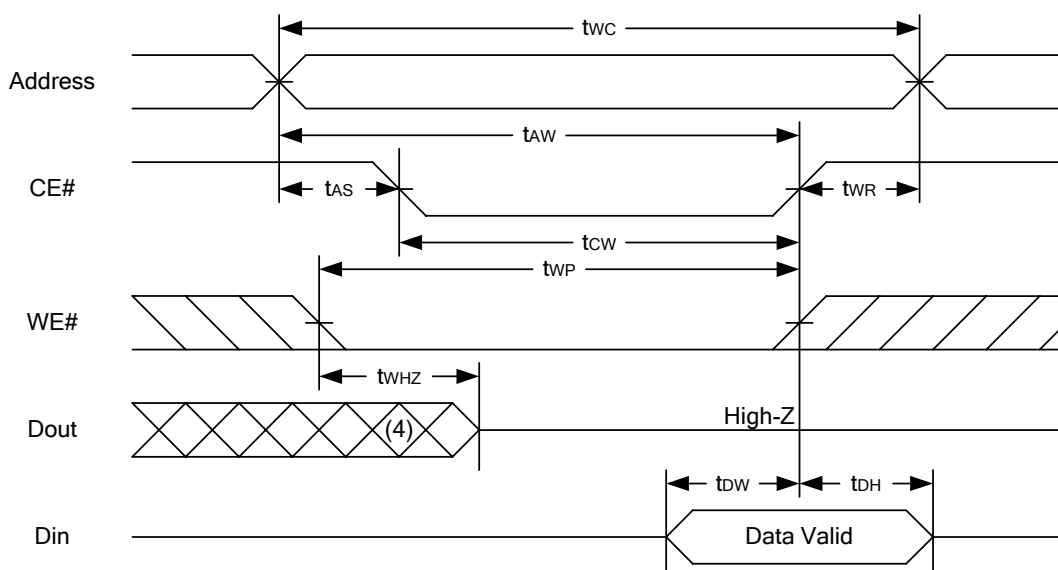


## 512K X 8 BIT LOW POWER CMOS SRAM

## WRITE CYCLE 1 (WE# Controlled) (1,2,3,5,6)



## WRITE CYCLE 2 (CE# Controlled) (1,2,5,6)



## Notes :

1. WE#, CE# must be high during all address transitions.
2. A write occurs during the overlap of a low CE#, low WE#.
3. During a WE# controlled write cycle with OE# low, twp must be greater than twhZ + tdW to allow the drivers to turn off and data to be placed on the bus.
4. During this period, I/O pins are in the output state, and input signals must not be applied.
5. If the CE# low transition occurs simultaneously with or after WE# low transition, the outputs remain in a high impedance state.
6. tow and twhZ are specified with CL = 5pF. Transition is measured  $\pm 500\text{mV}$  from steady state.

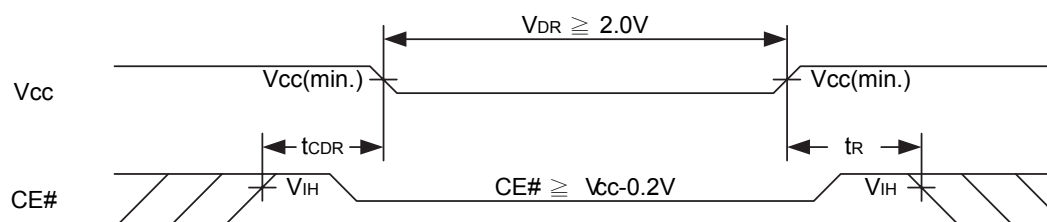


## 512K X 8 BIT LOW POWER CMOS SRAM

**DATA RETENTION CHARACTERISTICS**

| PARAMETER                           | SYMBOL           | TEST CONDITION                       | MIN.              | TYP. | MAX. | UNIT    |
|-------------------------------------|------------------|--------------------------------------|-------------------|------|------|---------|
| V <sub>CC</sub> for Data Retention  | V <sub>DR</sub>  | CE# $\geq$ V <sub>CC</sub> - 0.2V    | 2.0               | -    | 5.5  | V       |
| Data Retention Current              | I <sub>DR</sub>  | V <sub>CC</sub> = 2.0V               | -                 | 2    | 30   | $\mu$ A |
|                                     |                  | CE# $\geq$ V <sub>CC</sub> - 0.2V    | -                 | 2    | 30   | $\mu$ A |
| Chip Disable to Data Retention Time | t <sub>CDR</sub> | See Data Retention Waveforms (below) | 0                 | -    | -    | ns      |
| Recovery Time                       | t <sub>R</sub>   |                                      | t <sub>RC</sub> * | -    | -    | ns      |

t<sub>RC</sub>\* = Read Cycle Time \*\*C=Commercial temperature/I=Industrial temperature

**DATA RETENTION WAVEFORM**

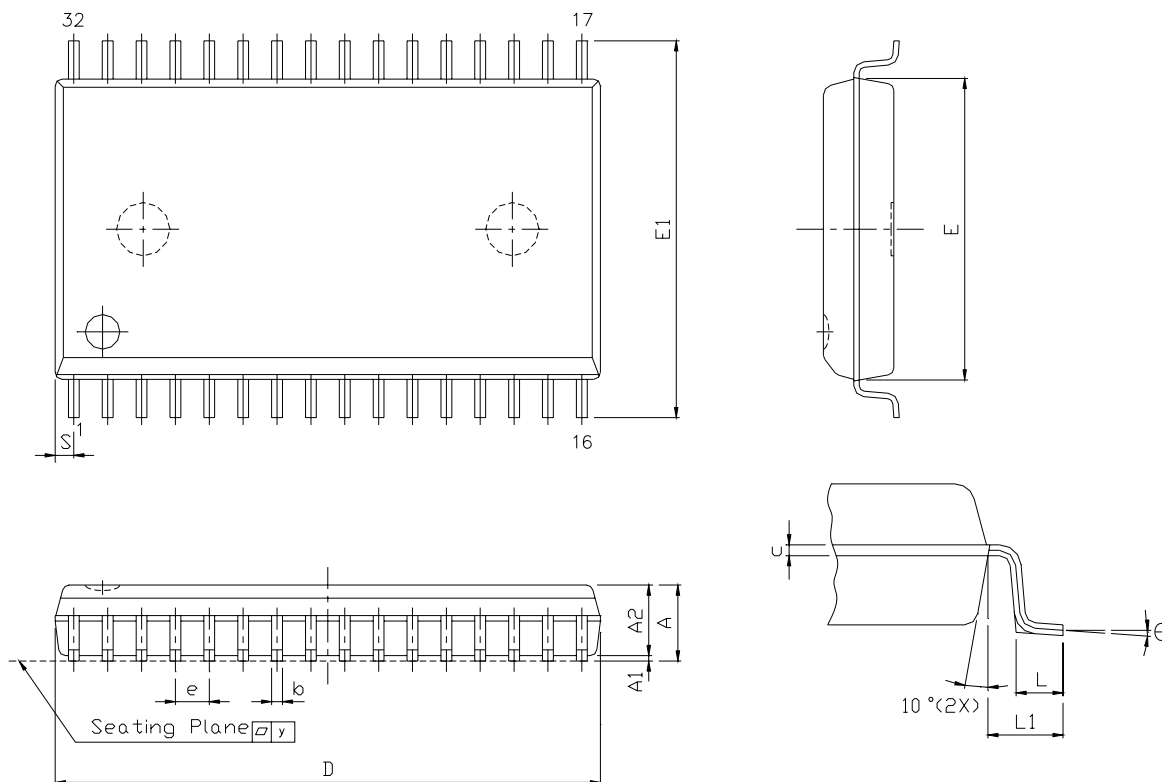




## 512K X 8 BIT LOW POWER CMOS SRAM

### PACKAGE OUTLINE DIMENSION

#### 32 pin 450 mil SOP Package Outline Dimension

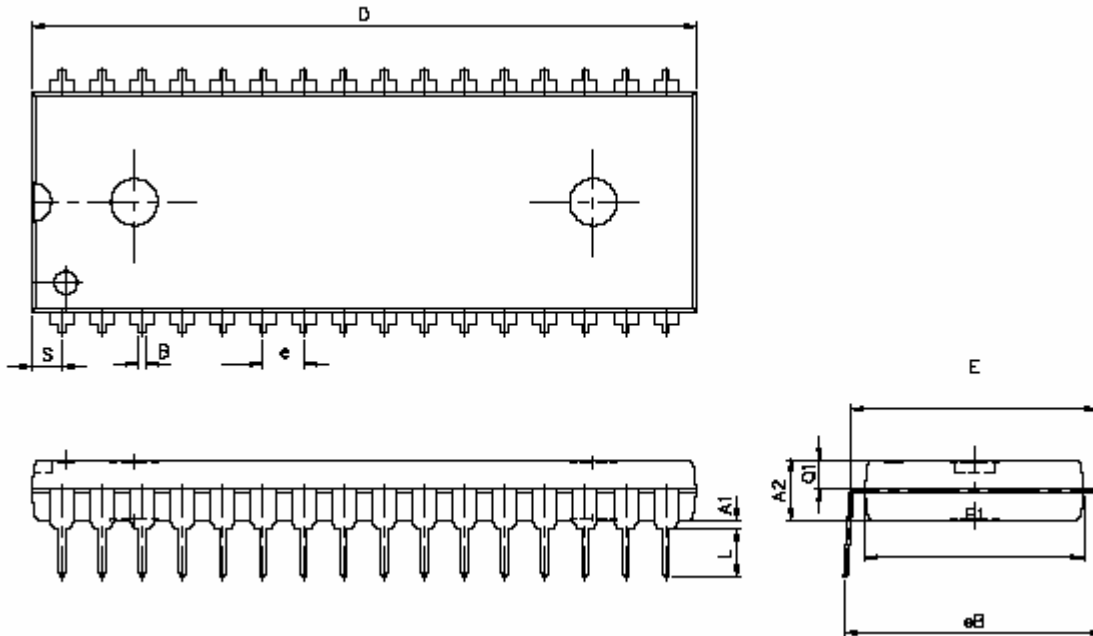


| SYM. | UNIT | INCH.(BASE)        | MM(REF)            |
|------|------|--------------------|--------------------|
| A    |      | 0.118 (MAX)        | 2.997 (MAX)        |
| A1   |      | 0.004(MIN)         | 0.102(MIN)         |
| A2   |      | 0.111(MAX)         | 2.82(MAX)          |
| b    |      | 0.016(TYP)         | 0.406(TYP)         |
| c    |      | 0.008(TYP)         | 0.203(TYP)         |
| D    |      | 0.817(MAX)         | 20.75(MAX)         |
| E    |      | 0.445 $\pm$ 0.005  | 11.303 $\pm$ 0.127 |
| E1   |      | 0.555 $\pm$ 0.012  | 14.097 $\pm$ 0.305 |
| e    |      | 0.050(TYP)         | 1.270(TYP)         |
| L    |      | 0.0347 $\pm$ 0.008 | 0.881 $\pm$ 0.203  |
| L1   |      | 0.055 $\pm$ 0.008  | 1.397 $\pm$ 0.203  |
| S    |      | 0.026(MAX)         | 0.660 (MAX)        |
| y    |      | 0.004(MAX)         | 0.101(MAX)         |
| Θ    |      | 0° -10°            | 0° -10°            |



## 512K X 8 BIT LOW POWER CMOS SRAM

### 32 pin 600 mil P-DIP Package Outline Dimension



| SYM. \ UNIT | INCH(BASE)    | MM(REF)         |
|-------------|---------------|-----------------|
| A1          | 0.001 (MIN)   | 0.254 (MIN)     |
| A2          | 0.150 ± 0.005 | 3.810 ± 0.127   |
| B           | 0.018 ± 0.005 | 0.457 ± 0.127   |
| D           | 1.650 ± 0.005 | 41.910 ± 0.127  |
| E           | 0.600 ± 0.010 | 15.240 ± 0.254  |
| E1          | 0.544 ± 0.004 | 13.818 ± 0.102  |
| e           | 0.100 (TYP)   | 2.540 (TYP)     |
| eB          | 0.640 ± 0.020 | 16.256 ± 0.508. |
| L           | 0.130 ± 0.010 | 3.302 ± 0.254   |
| S           | 0.075 ± 0.010 | 1.905 ± 0.254   |
| Q1          | 0.070 ± 0.005 | 1.778 ± 0.127   |

Note : D/E1/S dimension do not include mold flash.



## 512K X 8 BIT LOW POWER CMOS SRAM

**ORDERING INFORMATION**

## Ordering Codes

| Alliance        | Organization | VCC range | Package                   | Operating Temp                 | Speed ns |
|-----------------|--------------|-----------|---------------------------|--------------------------------|----------|
| AS6C4008-55PCN  | 512k x 8     | 2.7-5.5V  | 32pin 600mil PDIP         | Commercial ~<br>0° C to 70° C  | 55       |
| AS6C4008-55SIN  | 512k x 8     | 2.7-5.5V  | 32pin 450mil SOP          | Industrial ~<br>-40°C to 85° C | 55       |
| AS6C4008-55TIN  | 512k x 8     | 2.7-5.5V  | 32pin TSOP-I (8 x 20 mm)  | Industrial ~<br>-40°C to 85° C | 55       |
| AS6C4008-55STIN | 512k x 8     | 2.7-5.5V  | 32pin sTSOP (8 x 13.4 mm) | Industrial ~<br>-40°C to 85° C | 55       |
| AS6C4008-55BIN  | 512k x 8     | 2.7-5.5V  | 36pin TFBGA (6mm x 8mm) * | Industrial ~<br>-40°C to 85° C | 55       |
|                 |              |           | <b>*Coming Soon!</b>      |                                |          |

## Part numbering system

| AS6C                           | 4008                                     | - 55           | X                                                                                                                                                                                | X                                                                                             | N                                          |
|--------------------------------|------------------------------------------|----------------|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|-----------------------------------------------------------------------------------------------|--------------------------------------------|
| low<br>power<br>SRAM<br>prefix | Device<br>Number<br>40 = 4M<br>08 = by 8 | Access<br>Time | Package Options:<br>P = 32 pin 600 mil P-DIP<br>S = 32 pin 450 mil SOP<br>T = 32 pin TSOP-I (8mm x 20 mm)<br>ST = 32 pin sTSOP (8mm x 13.4 mm)<br>B = 36 pin TFBGA (6mm x 8mm) * | Temperature Range:<br>C = Commercial<br>(0°C to +70° C)<br>I = Industrial<br>(-40° to +85° C) | N = Lead<br>Free ROHS<br>Compliant<br>Part |

\* Coming Soon!